

Flexprint Design Studies for the Mu3e Experiment

Jens Kröger

on behalf of the Mu3e collaboration

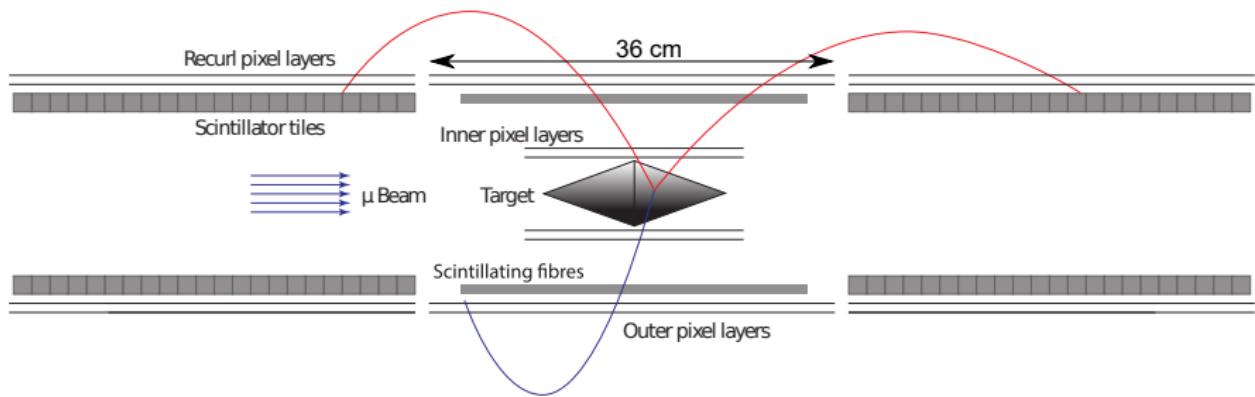
DPG Frühjahrstagung Münster 2017

March 28, 2017



The Mu3e Experiment - Detector Concept

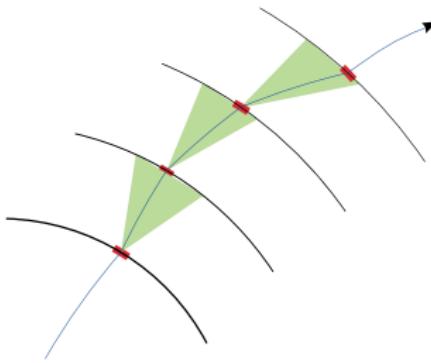
- μ^+ are stopped
- decay at rest
→ low momentum electrons $p_e \leq 53 \text{ MeV}/c$
- 1 T magnetic field



The Mu3e Experiment - Detector Concept

- low momentum electrons
 $p_e \leq 53 \text{ MeV}/c$
- **multiple Coulomb scattering**
dominates momentum resolution

$$\Theta_{rms} \propto \sqrt{\frac{x}{X_0}}$$



tracking in scattering dominated regime

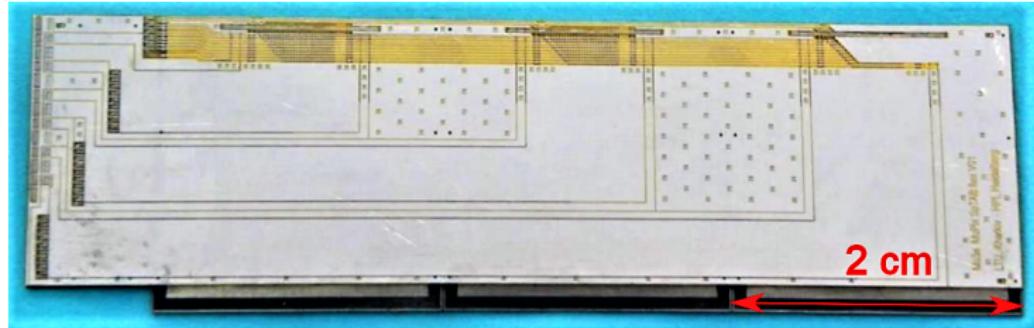
→ **consequence:** minimize material budget

Flexprints for the Mu3e Detector

Challenge: minimize material budget

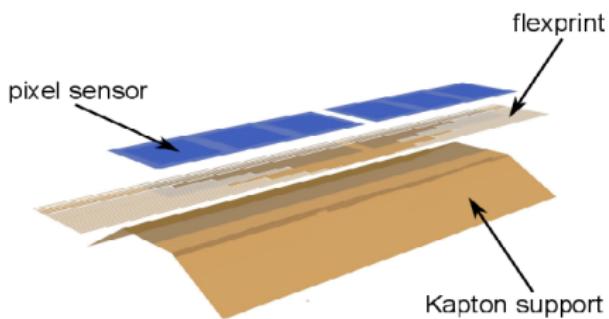
Solution: thinned pixel chips and flexprints

- dielectric layers:
polyimide film (Kapton)
- electric layers: copper or aluminium



Flexprints for the Mu3e Detector

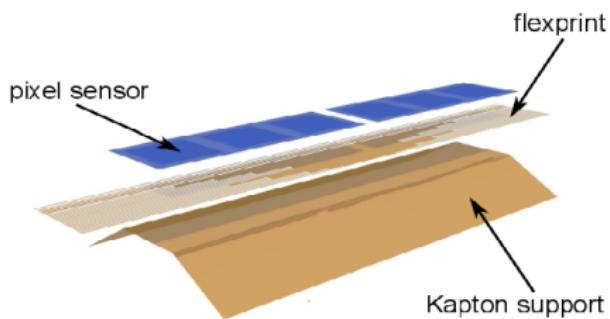
- desired material budget:
 $x/X_0 \leq 0.1\%$ per layer



	x/X_0
pixel chip (50 μm)	$\sim 0.05\%$
flexprint	$\sim 0.05\%$
support + glue (35 μm)	$\sim 0.01\%$
per layer	$\sim 0.11\%$

Flexprints for the Mu3e Detector

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	x/X_0
pixel chip (50 μm)	$\sim 0.05\%$
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support + glue (35 μm)	$\sim 0.01\%$
per layer	$\sim 0.11\%$

Experiment	x/X_0 per layer
ATLAS IBL [1]	1.9 %
CMS (upgrade) [2]	$\sim 1.1\%$
ALICE (upgrade) [3]	0.3 %
STAR [4]	0.4 %
BELLE II IBL [5]	0.2 %
Mu3e	$\sim 0.1\%$

Flexprints for the Mu3e Experiment

Aluminium vs. Copper

	conductivity	radiation length
Cu	$59.6 \times 10^6 \text{ S m}^{-1}$	1.436 cm
Al	$36.9 \times 10^6 \text{ S m}^{-1}$	8.897 cm



from wikipedia [6]



from wikipedia [7]

Flexprints for the Mu3e Experiment

Aluminium vs. Copper

	conductivity	radiation length
Cu	1.5× higher	
Al		6× longer

⇒ Aluminium saves us a **factor of 4** in material!



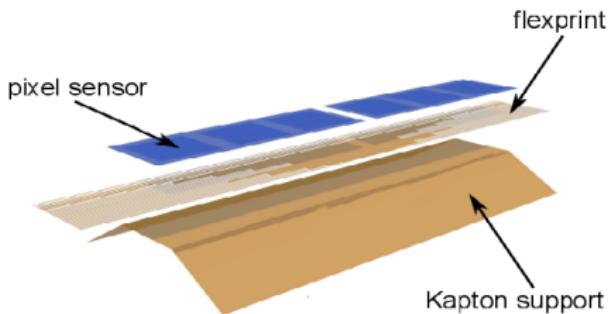
from wikipedia [6]



from wikipedia [7]

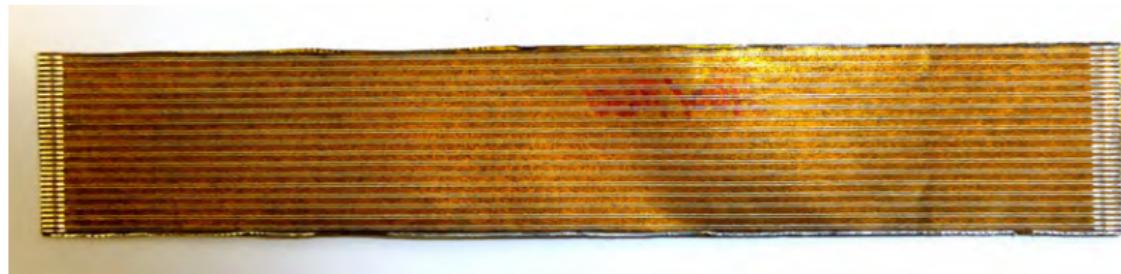
The Mu3e Experiment - Flexprint Requirements

- fast data transmission
(1.25 Gb/s LVDS)
- power supply and slow control
 - power $\leq 400 \text{ mW/cm}^2$
 - high voltage $\mathcal{O}(-100 \text{ V})$
 - clock, reset, configuration signals



Flexprint Prototypes - First Steps

In-house production with laser platform

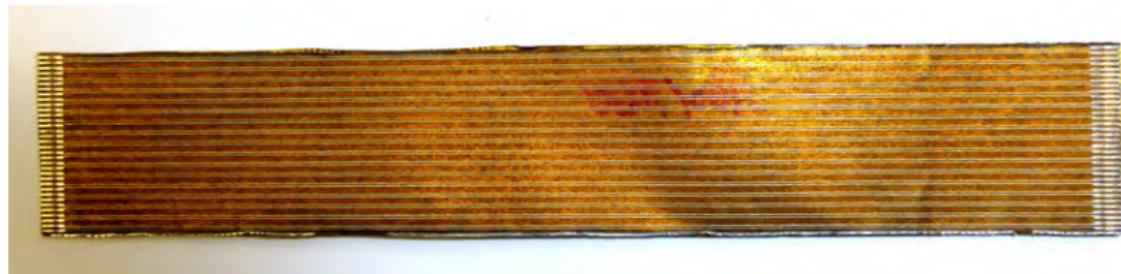


First flexprint: $10 \times 1.8 \text{ cm}^2$

- $25 \mu\text{m}$ Kapton + $25 \mu\text{m}$ Al + glue
- trace width $\geq 120 \mu\text{m}$,
trace separation $\geq 120 \mu\text{m}$
- different lengths up to 1 m

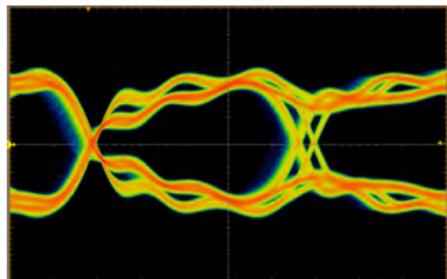
Flexprint Prototypes - First Steps

In-house production with laser platform



First flexprint: $10 \times 1.8 \text{ cm}^2$

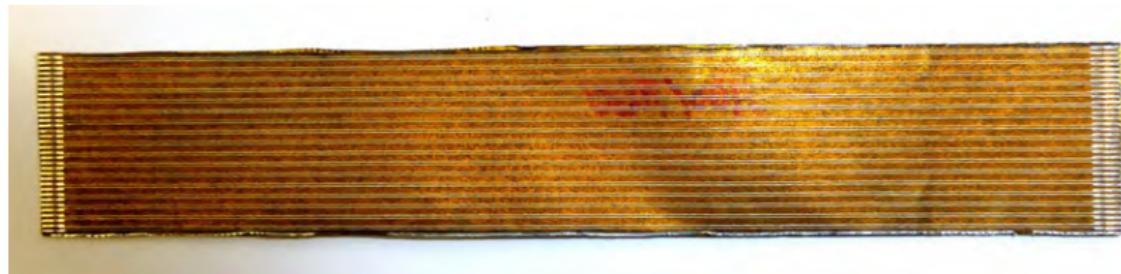
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Eye diagram at 800 Mb/s ,
length: 10 cm

Flexprint Prototypes - First Steps

In-house production with laser platform

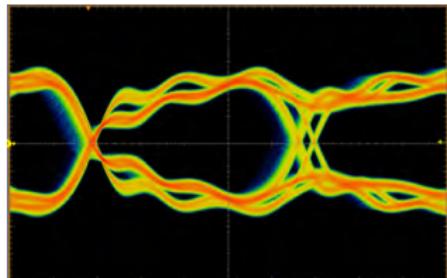


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Problem:

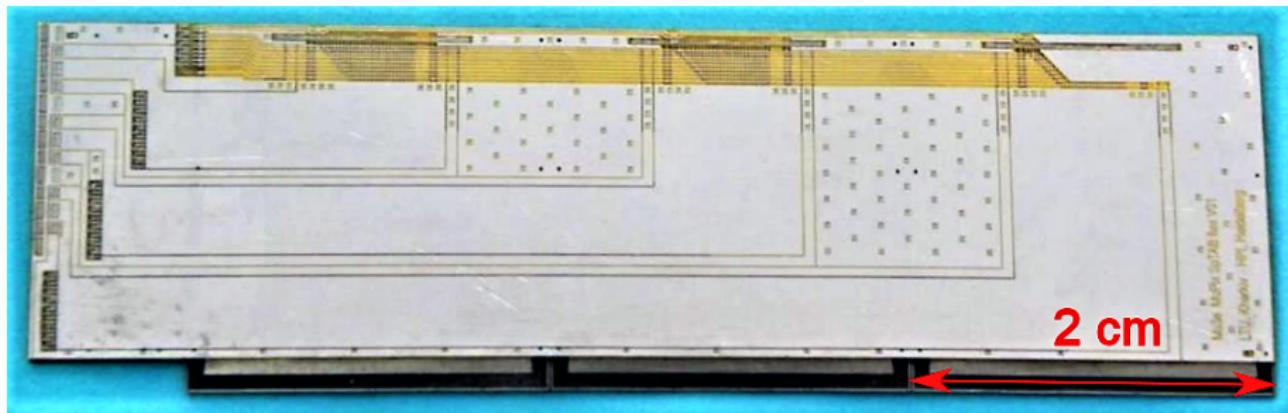
structures not small enough!



Eye diagram at 800 Mb/s,
length: 10 cm

First LTU Flexprint Prototype

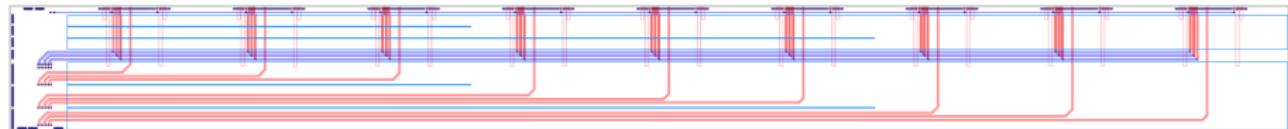
- manufactured by LTU
- smallest structure sizes: $63\text{ }\mu\text{m}$ → **sufficiently small**
- 3 dummy chips glued on flexprint
- only mechanical test



Flexprint Study for Outer Layers

Feasibility study (Bachelor Thesis by Lars Noehte, 2016 [8])

- 9 pixel chips over 18 cm
- min. number of signal traces
- power distribution critical

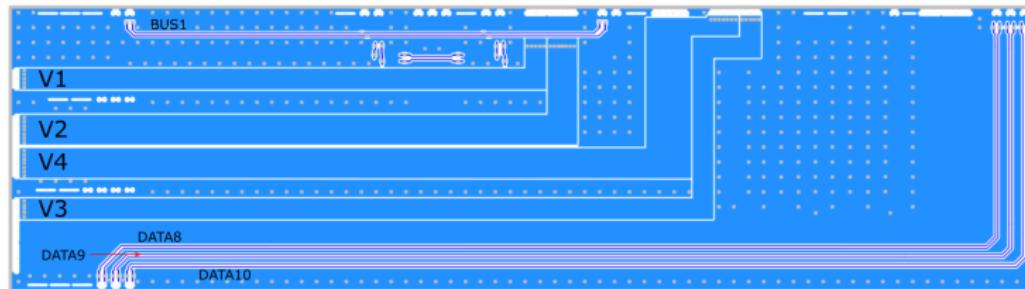


size: $1.8 \times 19.0 \text{ cm}^2$

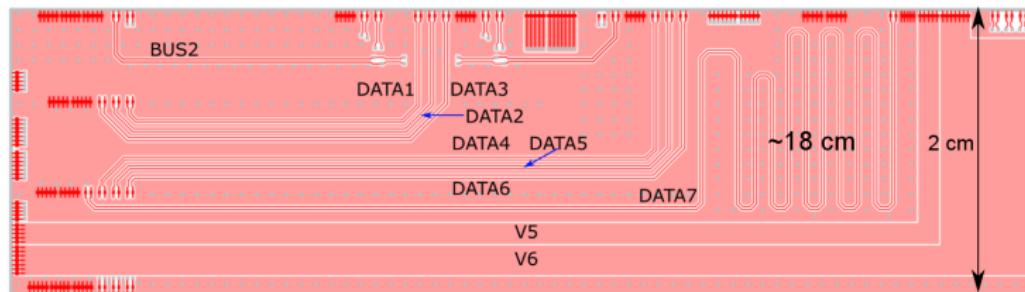
⇒ Next step: **Design test structure with all critical characteristics**

Flexprint Prototypes - Test Structure

Design containing all crucial characteristics for final design



top layer

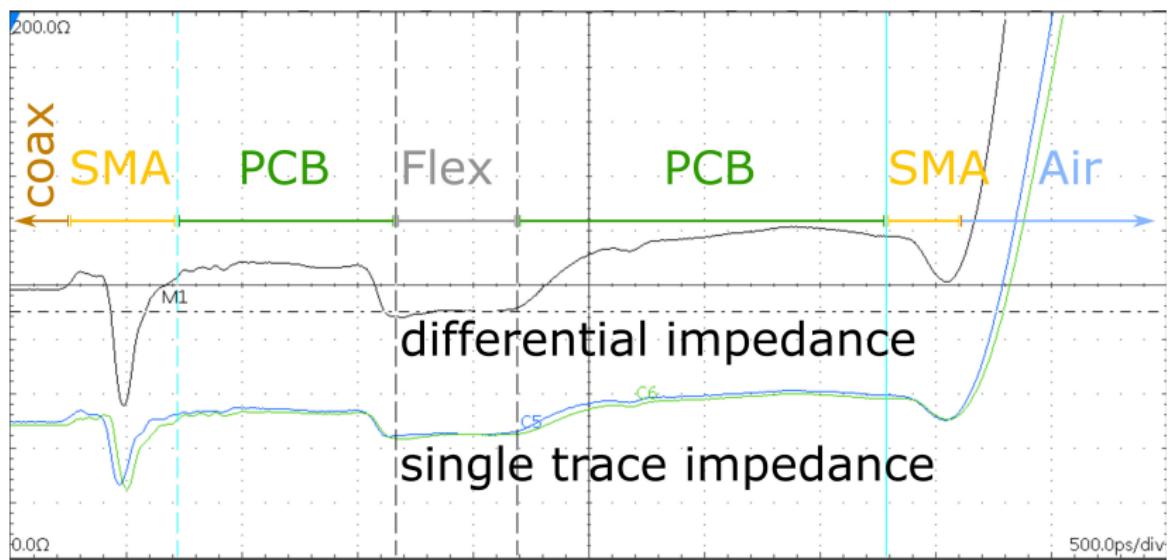


bottom layer

Flexprint Prototypes - Test Structure

Time Domain Reflectometry (TDR)

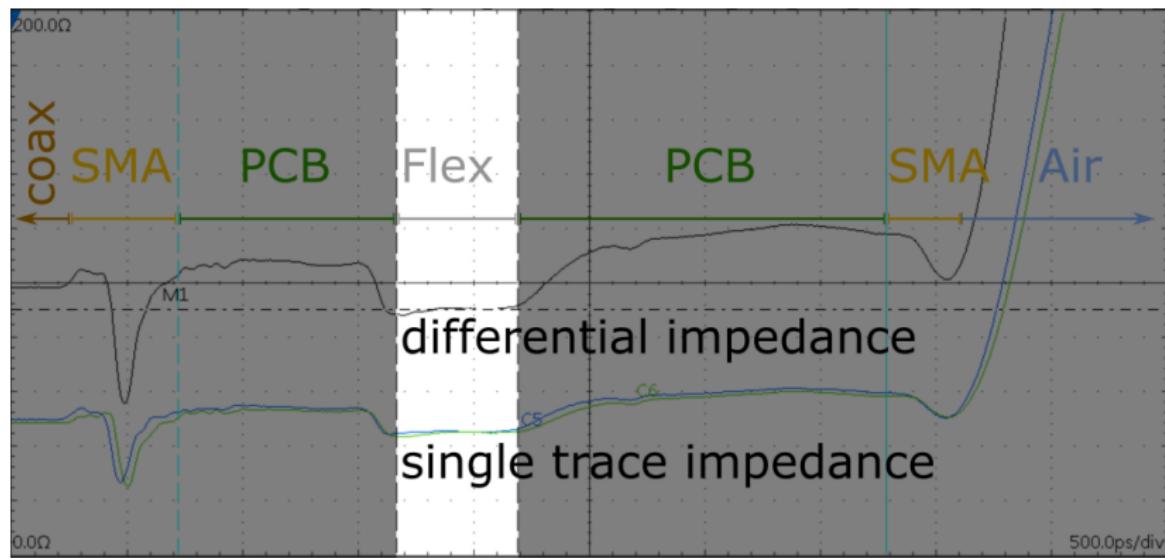
- measure impedance via reflection of input pulse
- essential for fast data transmission: $Z_0 = 50\Omega$, $Z_{diff} = 100\Omega$



Flexprint Prototypes - Test Structure

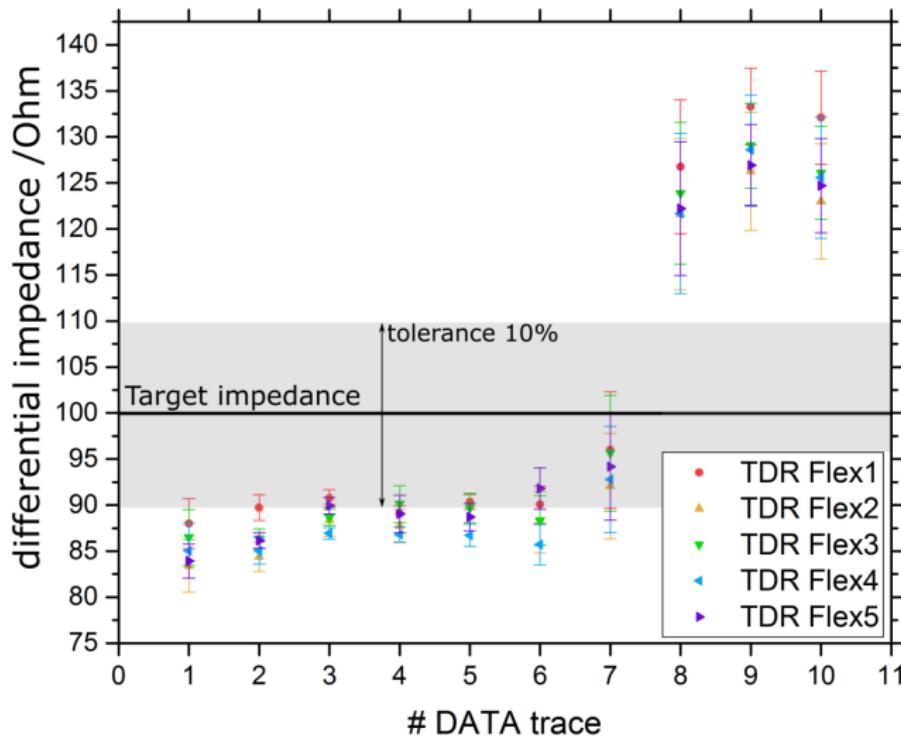
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Flexprint Prototype - Test Structure

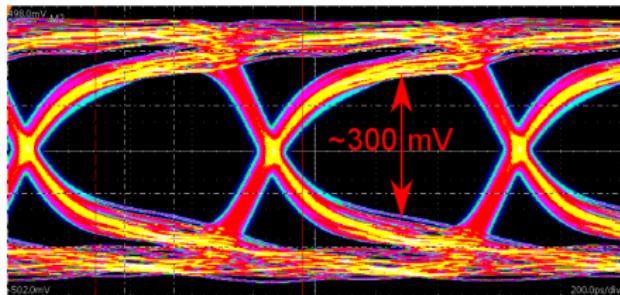
Time Domain Reflectometry (TDR)



Flexprint Prototypes - Test Structure

Data Transmission Studies

- eye diagram analysis



Eye diagram at 1.25 Gb/s

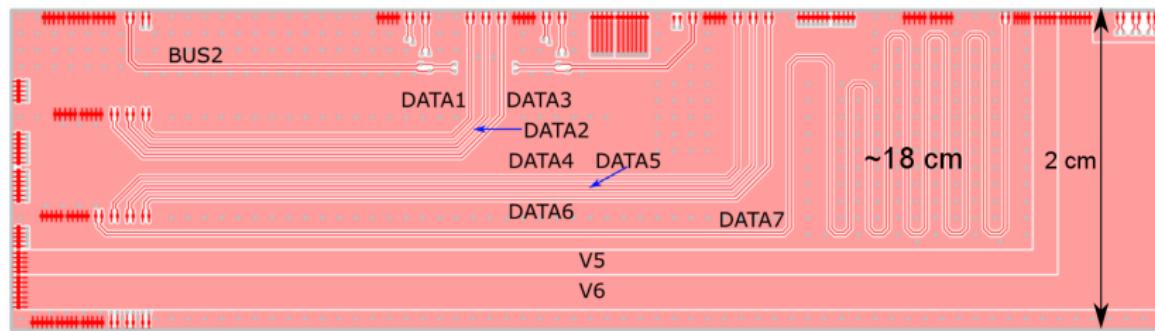
- bit error rate test
→ transmit pseudo random bit stream

$$BER = \frac{\# \text{ error bits}}{\# \text{ transmitted bits}}$$

Flexprint Prototypes - Test Structure

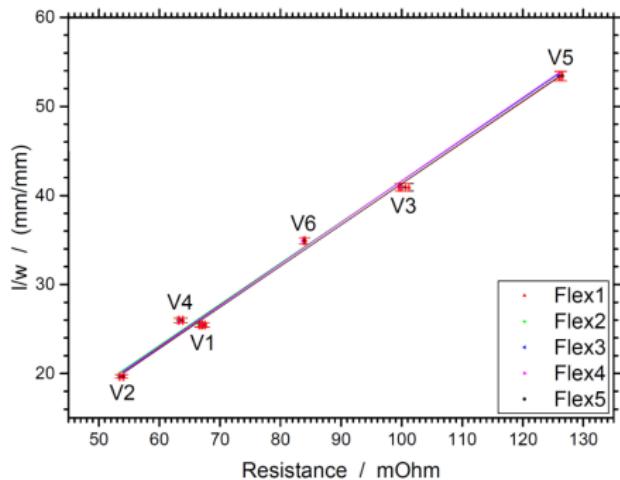
Bit Error Rate Test

data rate [Gb/s]	line	BER	upper limit at 95% CL
1.25 Gb/s	all	$\leq 5.5 \times 10^{-13}$	
2.5 Gb/s	all	$\leq 5.9 \times 10^{-13}$	
3.2 Gb/s	all short 18 cm	$\leq 4.1 \times 10^{-13}$	fail
4.0 Gb/s	all	fail	

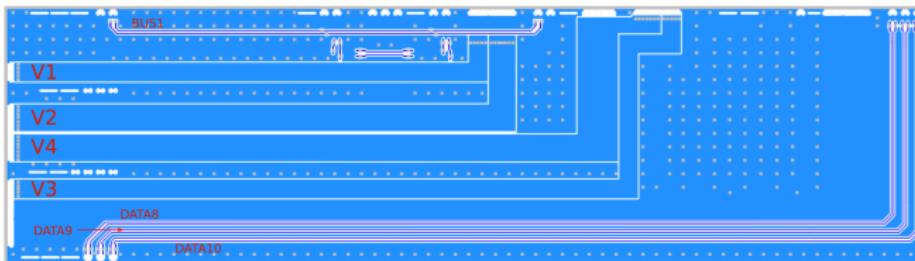


Flexprint Prototype - Test Structure

Power Planes



- manufacturer:
Al thickness $\sim 14 \mu\text{m}$
- $R = R_0 + \rho_{\text{Al}} \frac{1}{t} \frac{l}{w}$
- thickness from resistance measurement:
 $t = 12.3 \pm 0.3 \mu\text{m}$
- no significant deviations between flexprints



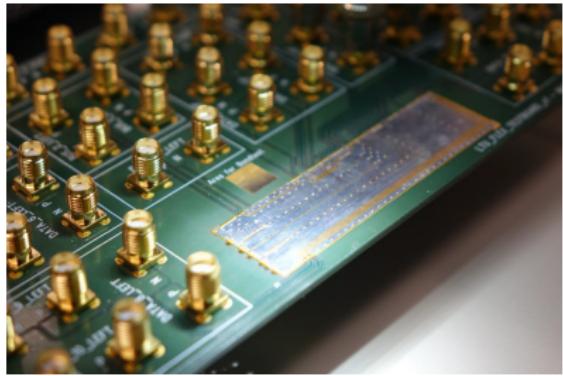
Flexprint Prototypes - Summary and Next Steps

Summary

- Mu3e: search for cLFV
- **ultra-low material** detector
- flexprints for readout and power supply of pixel tracker
- very promising
 - **bit error rate tests** and
 - **power tests**

Next Steps

- improve trace parameters
- operate **one** pixel chip on a flexprint
- operate **multiple** pixel chips on a flexprint



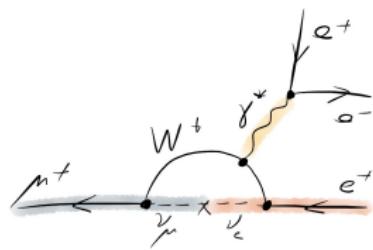
References

- [1] ATL-INDET-PROC-2015-001
- [2] CERN-LHCC-2012-016, CMS-TDR-11
- [3] arXiv:1211.4494v1
- [4] talk by G. Contin at PIXEL 2016
- [5] talk by C. Koffmane at PIXEL 2016
- [6] <https://upload.wikimedia.org/wikipedia/commons/f/f0/NatCopper.jpg>
- [7] <https://upload.wikimedia.org/wikipedia/commons/5/5d/Aluminium-4.jpg>
- [8] L. Noehete, *Flexprint design and characterization for the Mu3e experiment*, Bachelor thesis, Heidelberg University, 2016,
<https://www.psi.ch/mu3e/ThesesEN/BachelorNoehete.pdf>

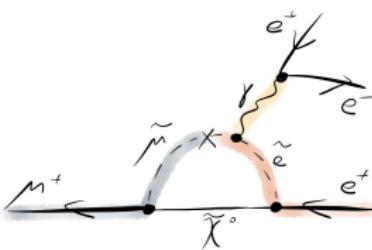
Backup

The Mu3e Experiment - Motivation

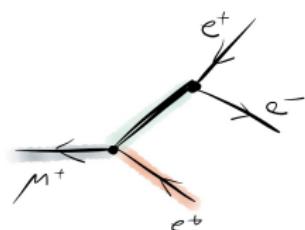
- search for lepton-flavour violating decay $\mu^+ \rightarrow e^+ e^- e^+$
- sensitivity: 1 in 10^{16} decays
- ν_{SM} branching ratio $\leq 10^{-54}$
- signal would be clear sign for BSM physics



SM process

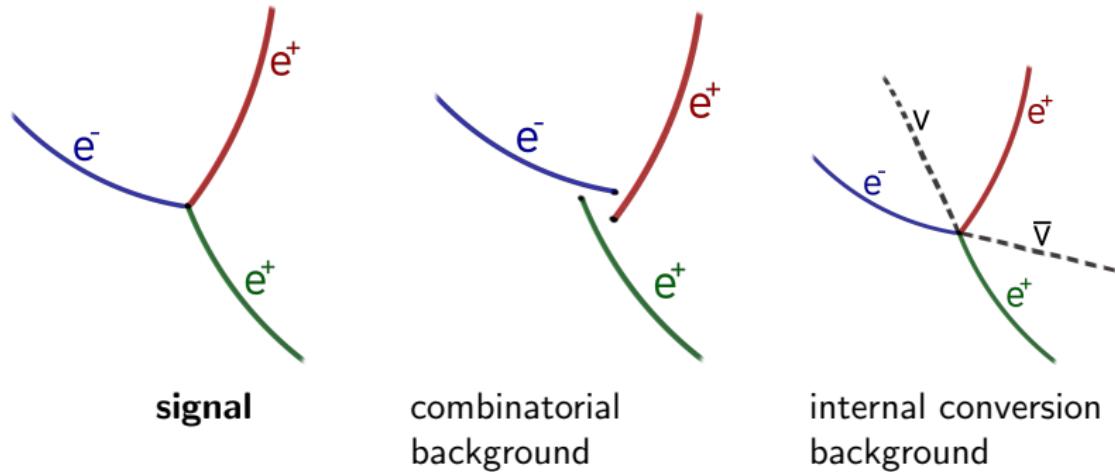


SUSY process



tree-level LFV process

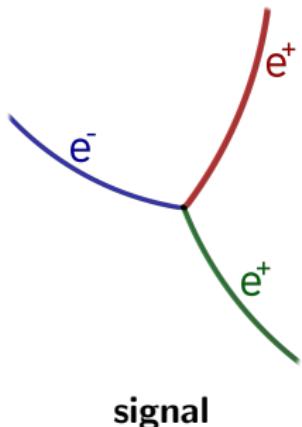
The Mu3e Experiment - Signal and Backgrounds



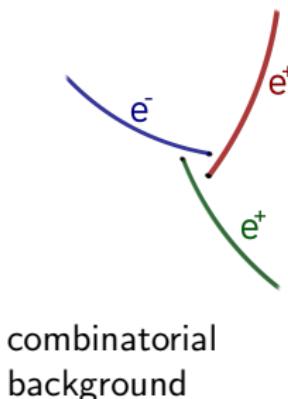
→ Detector Requirements:

- very high vertex resolution
- excellent momentum reconstruction

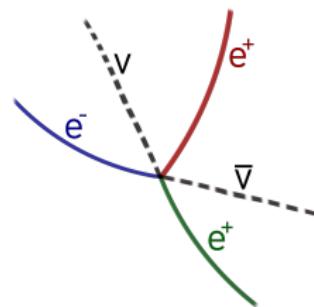
The Mu3e Experiment - Signal and Background Topologies



signal



combinatorial
background



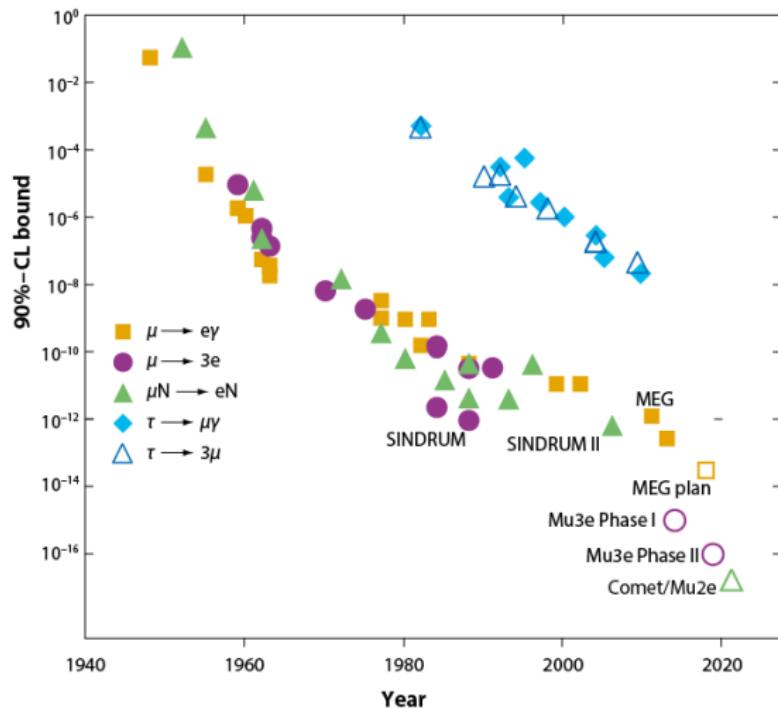
internal conversion
background

- common vertex
- coincident (in time)
- $\sum \vec{p} = 0$
- $\sum E = m_\mu$

- no common vertex
- not coincident (in time)
- $\sum \vec{p} = 0$
- $\sum E = m_\mu$

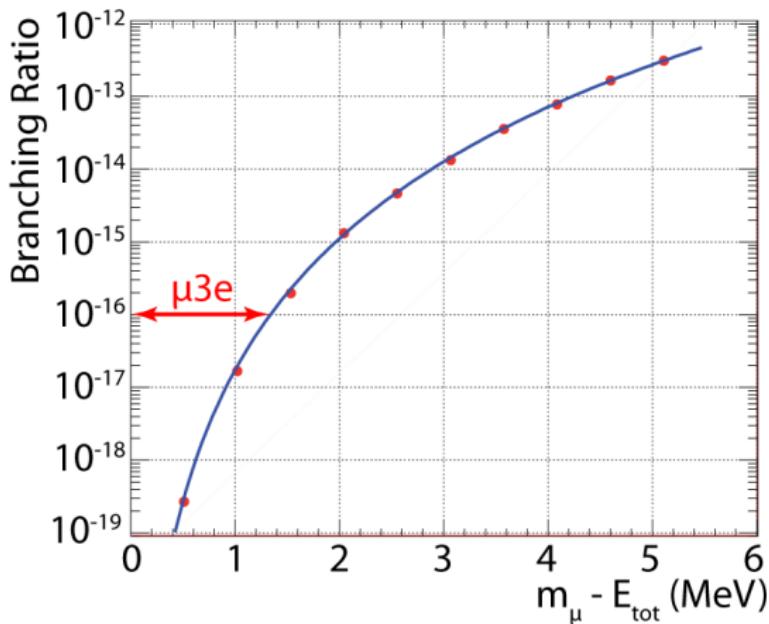
- common vertex
- coincident (in time)
- $\sum \vec{p} \neq 0$
- $\sum E \neq m_\mu$

History of LVF Experiments



Updated from W.J. Marciano et al., Ann.Rev.Nucl.Part.Sci. 58, 315 (2008)

E_{miss} Resolution Requirement for Mu3e



R.M. Djilkibaev and R.V. Konoplich, Rphzs.Rev., D79 073004, 2009